



10/8/10

**RELIABILITY MONITOR REPORT
FOR**

MFN 80V Bipolar CMOS DMOS (BCD88)

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX5026EUT+	MAX5026EUT+T
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The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 20735 QUANTITY: 134 FAILS: 0 FITS: 5.5

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 10/1/2009 and 9/30/2010 .

Process Information:

Process Description: MFN 80V Bipolar CMOS DMOS (BCD88)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1007	MAX5026EUT+T	135C	500 HRS	54	0	J3I0E2011BB
HIGH TEMP OP LIFE	1007	MAX5026EUT+T	135C	1000 HRS	80	0	J3I0E2012CB
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	0936	MAX5026EUT+	-65C TO 150C	1000 CYS	80	0	J3I0EA007GC
Total:						0	

FAILURE RATE: MTTF (YRS): 20735 QUANTITY: 134 FAILS: 0 FITS: 5.5